

## Cleanliness Evaluation as per IEST-STD-CC1246D

<b>Sample Name:</b>	ABC123	<b>Calibration:</b>	1.4784 µm/pixel
<b>Sample Size:</b>	4 inch wafer	<b>Magnification:</b>	50X
<b>Number of Samples:</b>	1	<b># Fields:</b>	489
<b>ID of replicate samples:</b>		<b>Target Level:</b>	100

<b>Date procured:</b>	2009-Jun-11	<b>Date tested:</b>	2009-Jun-11
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**Additional Information:**

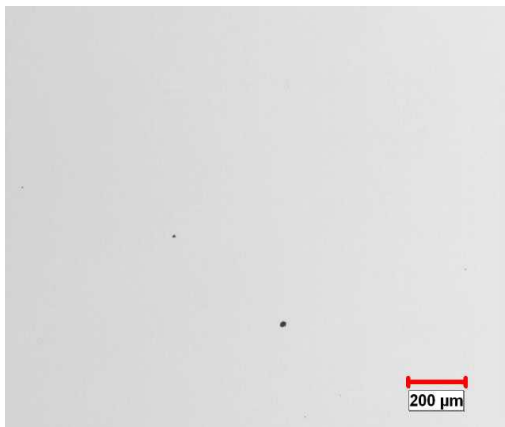
Complete surface analyzed  
 Operating condition of item during test procurement  
 Environment in which sample was taken  
 Equipment used to take sample  
 Method used to obtain sample  
 Method used to perform test

**Results**

<b>Total area analyzed:</b>	1386692127 mic2	<b>Normalized to 0.1 m2</b>	0.1 m2
<b>Total particle count:</b>	23		1658.6
<b>Total particle area:</b>	985.735611 mic2		71085.4 mic2

**Percent Area Coverage:** 0.000071 %  
**UCL** 34.5  
**LCL** 15.3

Particle Size (mic)	Max. concentration for 0.1 m2	Count (normalized)	Over
5	1784.8	1658.6	No
15	265.0	216.3	No
25	78.4	72.1	No
50	10.7	0.0	No
100	1.0	0.0	No



Largest particle found.

